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PATENT APPLICATION

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IN THE U.S. PATENT AND TRADEMARK OFFICE

April 14, 2006

Applicants : Atsushi YABE et al

For : ELECTROLESS COPPER PLATING SOLUTION AND  
ELECTROLESS COPPER PLATING METHOD

PCT International Application No.: PCT/JP2004/014049

PCT International Filing Date: September 17, 2004

U.S. Application No.

(if known, see 37 CFR 1.5): Unknown

Atty. Docket No.: 4700.P0328US

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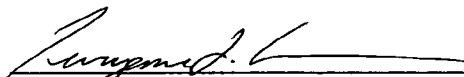
**INFORMATION DISCLOSURE STATEMENT**

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is a copy of the International Search Report, Form PTO-1449 and the references cited thereon. D1-D6 have been discussed in the specification. D7 is cited in the International Search Report. D7 and D8 are cited in the International Preliminary Examination Report. These references constitute the art known to the Applicants and are believed to be distinguishable from the claimed invention. Accordingly, further comment at this point in time should not be necessary.

Further consideration is respectfully solicited.

Respectfully submitted,

  
Terrence F. Chapman

TFC/smd

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Encl: Copy of International Search Report  
Form PTO-1449 and one copy of each listed reference

336.05/03

INFORMATION  
DISCLOSURE  
CITATION

Applicant: Atsushi YABE et al

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## U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA			
	AB			
	AC			
	AD			
	AE			
	AF			

## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AG	JP 2002-249879	09-06-2002	ITABASHI et al	Abstract
	AH	JP 57-501922	10-28-1982	PERSSON et al	Abstract
	AI	WO 01/49898 A1	07-12-2001	IMORI et al	Abstract
	AJ	WO 03/091476 A1	11-06-2003	IMORI et al	Abstract
	AK	WO 2004/108986 A1	12-16-2004	IMORI et al	Abstract
	AL	JP 6-256358	09-13-1994	TSUCHIDA et al	Abstract
	AM	JP 8-199369	08-06-1996	KONDO et al	Abstract
	AN	JP 2003-193245	07-09-2003	SEKIGUCHI et al	Abstract

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AO	
	AP	
EXAMINER SIGNATURE		DATE CONSIDERED
/Katherine A. Bareford/		05/05/2008

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.